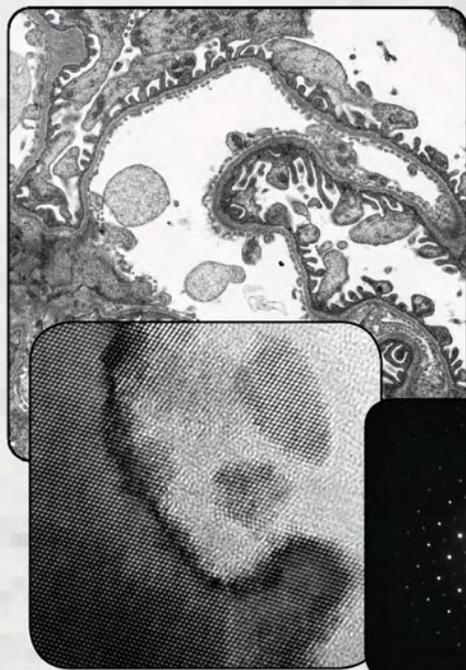


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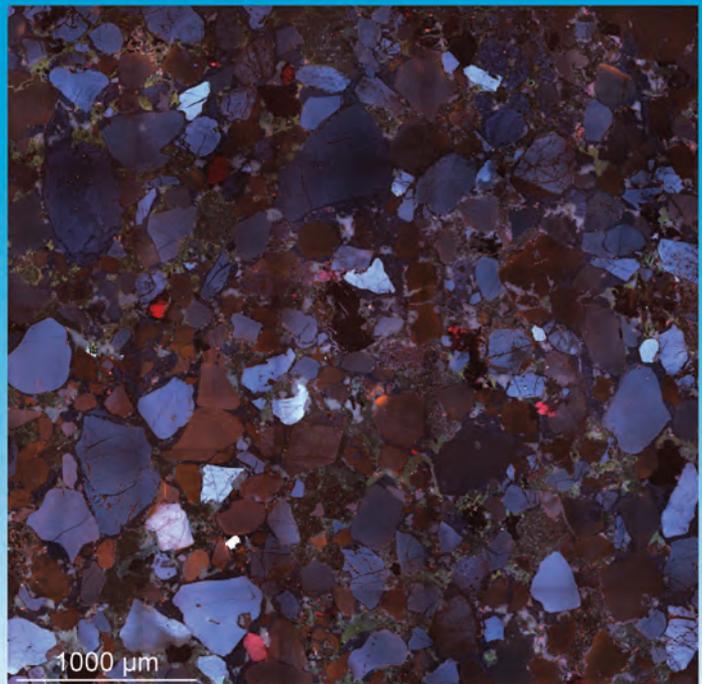
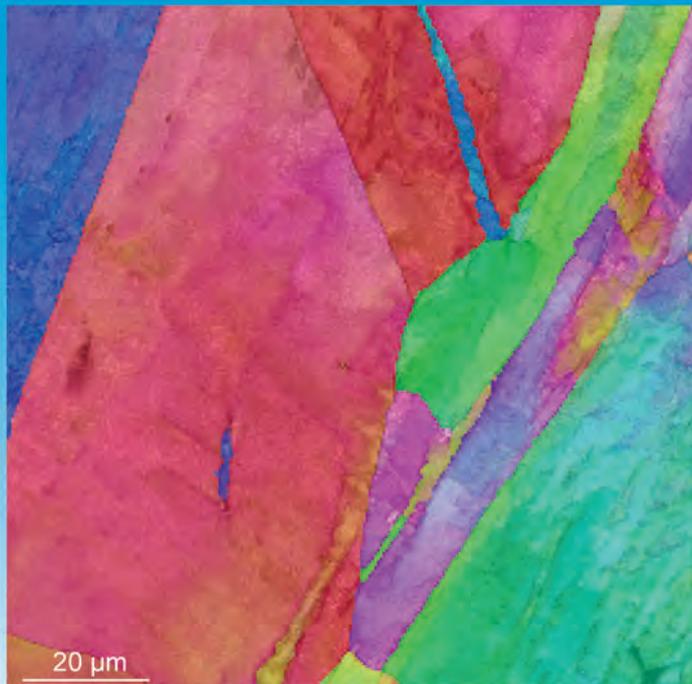
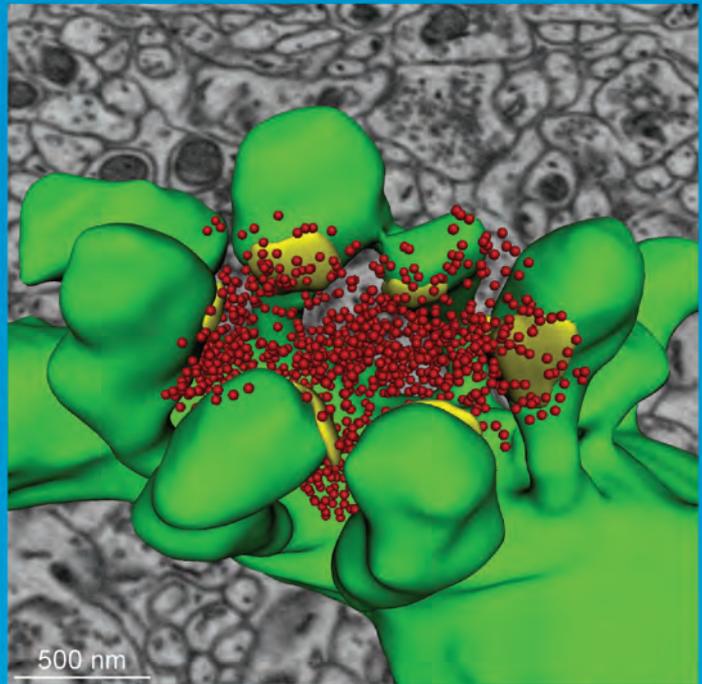
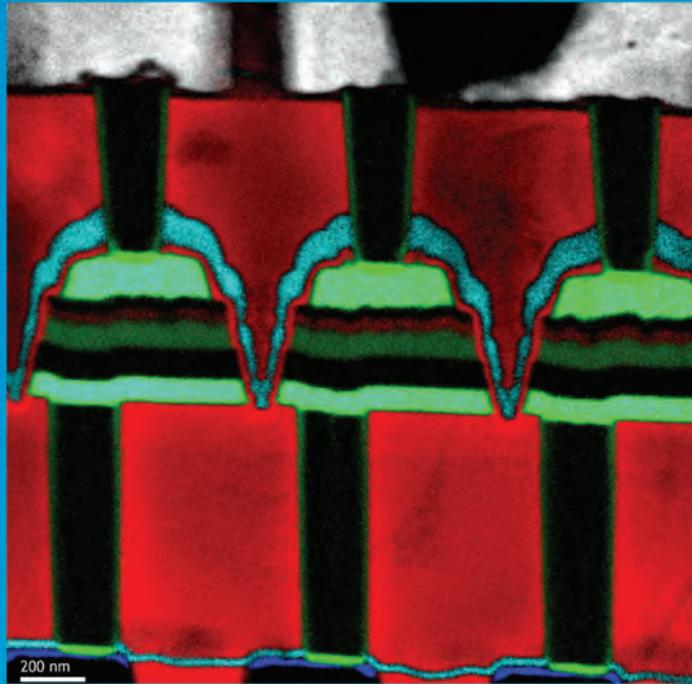
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Images (clockwise from top left): **Analytical TEM:** High-speed STEM EELS mapping of a commercial semiconductor device. Grey: Cu $L_{2,3}$ -edges; Red: O K-edge; Blue: Co $L_{2,3}$ -edges; Green: Ti $L_{2,3}$ -edges; Light Blue: N K-edge. Data were extracted from a 520 x 520 EELS spectrum image (2 GB dataset) acquired in 5 minutes at 1000 spectra per second, high-speed EELS acquisition mode. Image captured using a Gatan GIF Quantum[™]ER EELS system mounted on a 200 kV LaB6 STEM. **Serial Block Face Imaging in the SEM:** A 3D reconstruction of a dendrite from a 15,625 μm^3 ($25 \times 25 \times 25 \mu\text{m}$) volumetric data set containing 500 serial images of mouse cerebellum generated by Gatan 3View[™]2. Sample courtesy of Tom Deerinck and Dr. Mark Ellisman, National Center for Microscopy and Imaging Research, University of California, San Diego. Serial images were segmented using Imaris to create a 3D model of a neuron of interest. **Live Color Cathodoluminescence Imaging in the SEM:** Reservoir quartz of mixed provenance displaying healed fractures and chemical overgrowths. Sample prepared using the Gatan Iliion[™] and super-image acquired using Gatan ChromaCL2[™] imaging system and CHFS32. **Surface Preparation for SEM Cross Section and Planar Viewing:** SEM cross section of copper indexed to 98% with EBSD and prepared using the Gatan Iliion[™].

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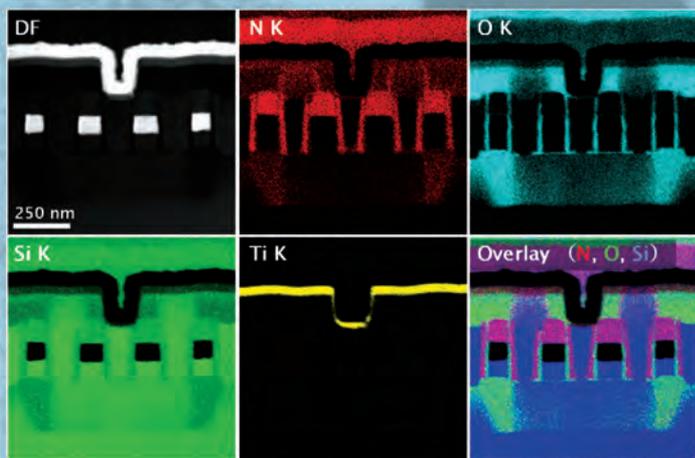
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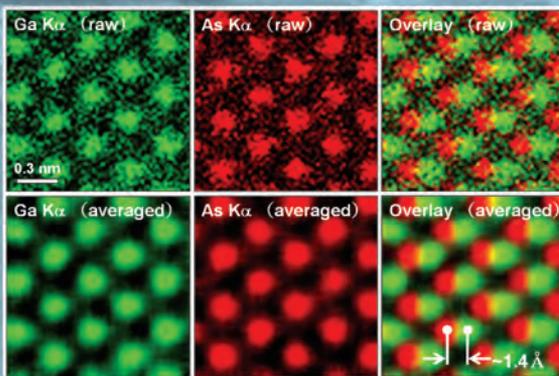


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